

Defect-oriented test- and layout-generation for standard-cell ASIC designs
Sudbrock, Joachim; **Raik, Jaan; Ubar, Raimund-Johannes**; Kuzmicz, Wieslaw; Pleskacz, Witold A. Proceedings : DSD'2005 : 8th Euromicro Conference on Digital System Design : Architectures, Methods and Tools : Porto, Portugal, August 30 - September 3, 2005 2005 / p. 79-82 : ill

Deterministic defect-oriented test generation for combinational circuits

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DOT: new deterministic defect-oriented ATPG tool

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